IN THE SPECIFICATION

Please replace the paragraph beginning on page 1, line 12 with the following:

Fig. 1 depicts a flow chart of the conventional method for testing a non-volatile memory. In step 101, it depicts the beginning of the flow chart of the conventional testing method. In step 102, an open /short test of the pins of the non-volatile memory is executed, if it is affirmative, step 103 is proceeded; otherwise, step 106 is proceeded and the memory is binned to binning category 2. In step 103, a functional test of the non-volatile memory is executed, if it is affirmative, step 104 is proceeded; otherwise, step 106 is proceeded with and the memory is binned to binning category 3. In step 104, an erasable and programmable test of the non-volatile memory is executed to determine whether the data of the non-volatile memory can be erased and new data can be rewritten in the memory or not, if it is affirmative, step 105 is proceeded; otherwise, step 106 is proceeded and the memory is binned to binning category 4. In step 105, a code test of the non-volatile memory is executed. In the code test, the code written in the non-volatile memory is read out and compared it with the original code. If the result is identical, step 106 is proceeded and the memory is binned to binning category 1; otherwise the memory is binned to binning category 5. All memory will be binned in step 106. In step 107, the flow chart of the conventional testing method ends.

Please replace the paragraph beginning on page 2, line 8 with the following:

In other words, the opening/shorting of the pins, logic function, erasable function and reading writing function of the memory can be checked in the conventional method, but it cannot be checked whether the code written in the memory is assigned by the client or not. For example, if the controlling program of the testing machine retrieves a code which is not

assigned by the client, the result of the read write function test will be ~~affirmative. Since~~

affirmative, since the read write function test of the memory is to read out the code written in

the memory and compare it with the code retrieved by the controlling program of the testing

machine.

Please replace the paragraph beginning on page 5, line 9 with the following:

Before proceeding with the flow chart of the present invention, a code assigned by the

client is written in a plurality of non-volatile memories with a write enabling pin (EA pin for

short in the present invention). Then, the EA pin of the non-volatile memory is cut to avoid

rewriting a code because of personal mistakes. The plurality of non-volatile memories

without the EA pin are treated as samples for testing whether the code retrieved by the

controlling program of the testing machine is assigned by the client or not. The pluralities of

non-volatile memories are referred to as first correlation sample or golden sample. Moreover,

a plurality of non-volatile memories passing the conventional testing method, shown in Fig.

1, are provided and treated as second correlation samples for checking whether the setting of

the testing machine is correct or not when it was restarted. After the first correlation sample

and the second correlation sample passed through the process of the present invention, the

process for testing the manufactured product is executed.

Please replace the paragraph beginning on page 6, line 6 with the following:

In step 207, an open/short test of the EA pin is executed. Only the second correlation

sample is tested at step 207, since the first correlation sample had been sorted out at step 202.

If the result of the open/short test of the EA pin is not short, step 208 is proceeded; otherwise,

3

step 211 is proceeded to bin the second correction sample to binning category 2. In step 208, a logic functional test of the second correlation sample is executed, if it passes, step 209 is proceeded; otherwise, step 211 is proceeded to bin the second correction sample to binning category 3. In step 209, an erasable and programmable test of the second correlation sample is executed to determine whether the data of second correlation sample can be erased and new data can be rewritten second correlation sample or not. If the result of step 209 is affirmative, step 210 is proceeded; otherwise, step 211 is proceeded and the second correction sample is binned to binning category 4. In step 210, a code test is executed that compares the code written in the second correlation sample with the code retrieved by the controlling program of the testing machine, so as to determine whether the read/write function of the second correlation sample is correct or not. If the result of step 210 is affirmative, step 211 is proceeded and the second correlation sample is binned to binning category 1; otherwise, the second correlation sample is binned to binning category 5. All of the second correlation samples are binned in step 211. In step 212, the flow chart of the present invention ends. Since the second correlation sample has been verified as a correct non-volatile memory, if there are any second correlation samples that are binned to the binning ~~category~~ categories 2,3,4 or 5, it means that the setting of the testing machine is incorrect and it needs to be adjusted before the process for testing the manufactured product is executed.

Please replace the paragraph beginning on page 7, line 6 with the following:

It should be noted that the first correlation sample with out the EA pin cannot be applied in the conventional ~~method, Since~~ method, since the first correlation sample will be binned to binning category 2 in the open/short test in step 102 of the conventional method,

4

and the code test will not be executed. In addition, if the EA pin of the memory of the manufactured product falls off because of carelessness during the process of the present invention, step 203 will be proceeded. Since this non-volatile memory has not been written with any code; the result of the code test is fail. Thus, the method according to the present invention can also be applied to the mass-production stage.